



*Industrial Computing Platform Partner*

# **AEC-6905 (ETX-821)**

**With CFD**

## **Temperature Cycle Test Report**

**Report NO: 07P020029**

**Issued by: Rex Chang / 10/17/2007**  

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**Test Engineer Date**

**Reviewed by: Wenyuan Yang / 10/17/2007**  

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**Manager Date**

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Num	Item	Spec
1.	<b>Embedded Controller:</b>	AEC-6905
	1. Main Board	AAEON ETX-821 Rev. A1.2-A
	2. BIOS	AEC-6905 0.5
	3. CPU	Intel Celeron -M / 1.5GHz
	4. Memory (Wide Temp.)	ATP 1GB / SAMSUNG K4H510838D-ZCCC / DDR333
	5. CFD (Wide Temp.)	Transcend 2GB
	6. Test Software	Windows XP Embedded / Run PassMark Burn In Test 5.1 Pro
	7. I/O Board	AAEON T095 A0.2
	8. Adapter	FSP FSP120-AAB (DC Output: 19V)

# Temperature cycle test

**Test Date:** 10-01~03-2007

**Test Product:** AEC-6905

**Test Site:** AAEON QA Internal Lab

**Performed By:** Rex Chang

**Test Standard:** Reference IEC68-2-14 Testing procedures  
Test Nb: Change of temperature Test

**Test Equipment:**

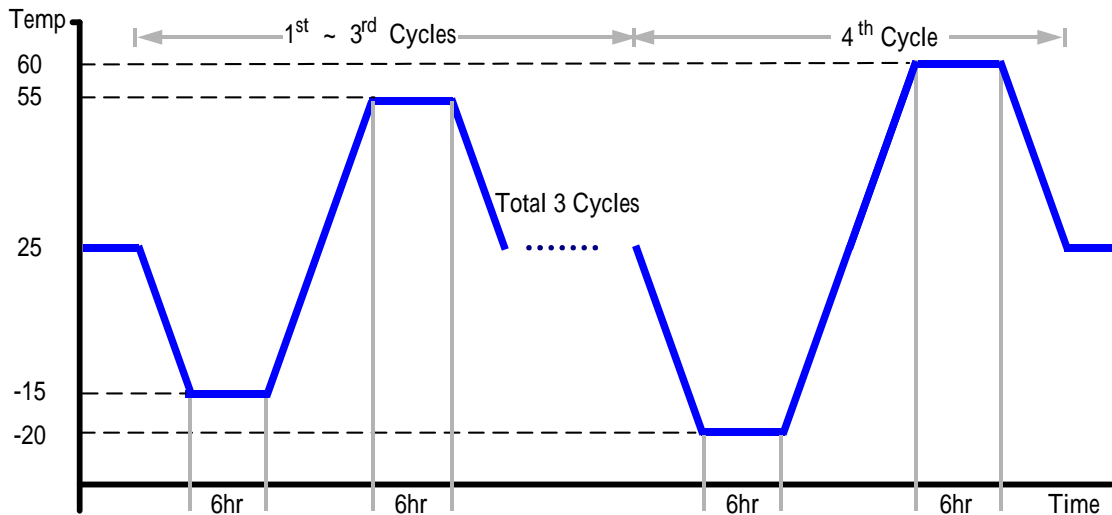
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-A4C-100  
Date of Calibration: 06/20/07  
Serial Number: 3188

**Temperature Measurement:**

40 Channel Thermal Recorder:  
YOKOGAWA Inc,  
Model: DA100-13-1D  
Date of Calibration: 12/11/06  
Serial Number: 12A323190

**Test Condition:**

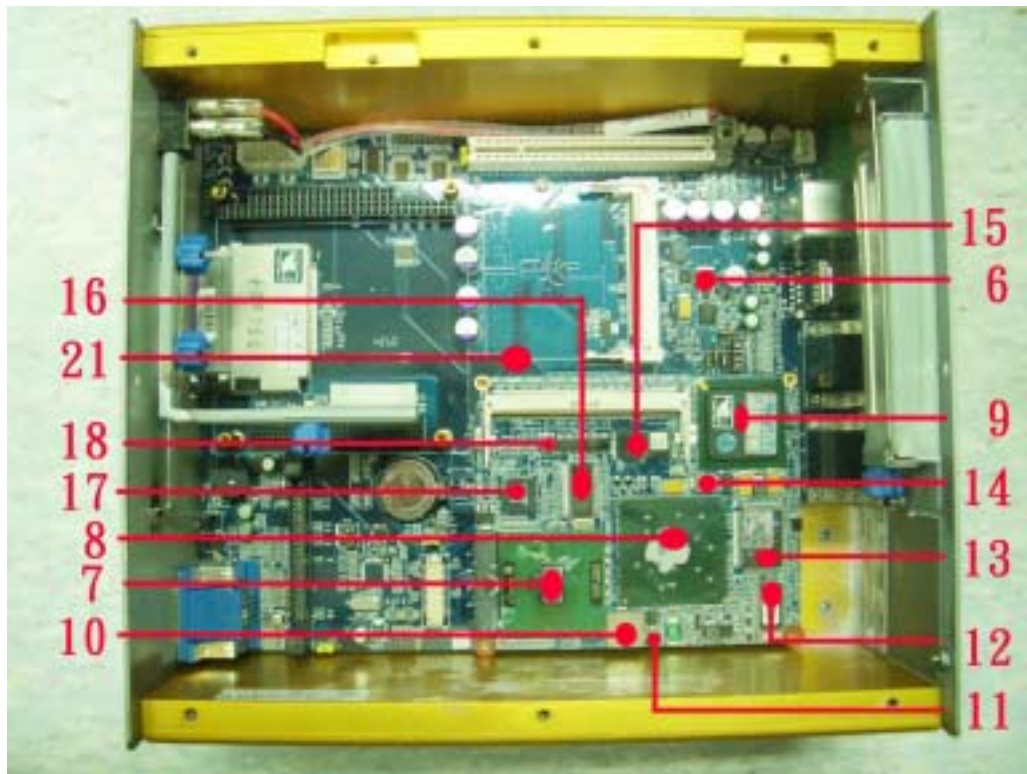
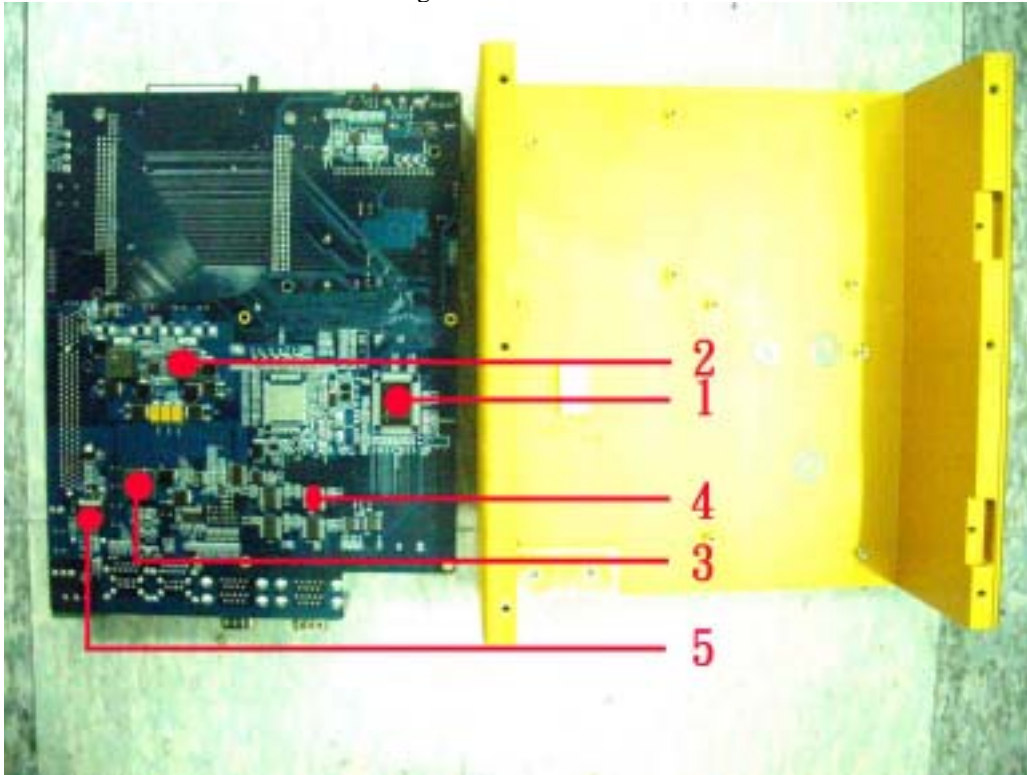
1. Test Low Temperature: -15 (1~3 cycles)  
-20 (4<sup>th</sup> cycle)
2. Test High Temperature: 55 (1~3 cycles)  
60 (4<sup>th</sup> cycle)
3. Test dwell time: 6Hrs
4. Temperature slope: 2 /min
5. Test cycle: 4 cycles
6. Test Environment Curve:



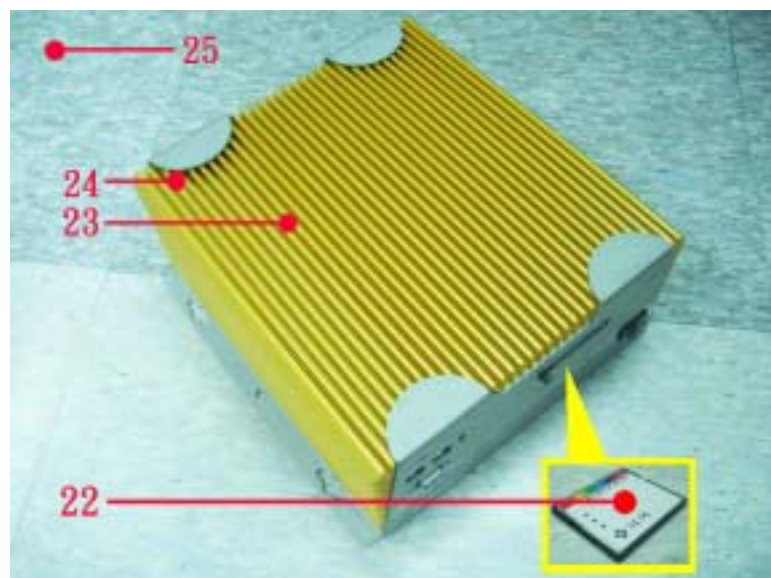
# Temperature cycle test

Terminal Recorder:

Measuring Accelerometer Position:



# Temperature cycle test



# Temperature cycle test

## Thermal profile data:

### AEC-6905

Point	Temp. Stage( )	Spec	55	25	-15
<b>I/O Board.T095. Rev: A0.2</b>					
1. U28 - (TF)IC.SMD.128P QFP Super I/O.Winbond.W83977EG-AW. Rev:H		95	69.8	39.8	-0.2
2. L42 - (TF)COIL.2.2uH.SMD.GOTREND.GSTC135P-2R2MF		95	68.1	38.1	-1.9
3. L36 - (TF) COIL.3.3uH.SMD.GOTREND.GSTC135P-3R3MF		125	66.8	36.8	-3.2
4. U19 - (TF) COIL.2.2uH.SMD.GOTREND.GSTC135P-2R2MF		125	78.3	48.3	8.3
5. U15 - (TF) COIL.2.2uH.SMD.GOTREND.GSTC135P-2R2MF		125	70.6	40.6	0.6
6. Q6 - (TF)PWR.SMD.TO-252AA.N-Channel MOSFET.FAIRCHILD.FDD5670		110	70.9	40.9	0.9
<b>ETX-821 A1.2-A</b>					
7. U1 - Intel Celeron -M / 1.5GHz		100	90.0	60.0	20.0
8. U3 - (TF)IC.SMD.BGA732.Chipset.NB82852GM.Intel.JG82852GM-SL7VP		105	85.5	55.5	15.5
9. U4 - (TF)IC.SMD.Chipset ICH4.INTEL.NH82801DB SL8DE		115	85.8	55.8	15.8
10. L5 - (TF)COIL.1.0uH.SMD.12.9*12.9*5mm. VISHAY.HLP5050EZER1R0M01		125	88.1	58.1	18.1
11. U14- (TF)PWR.SMD SO8.N-Channel MOSFET 30V 15A.FAIRCHILD.FDS8896		125	94.9	64.9	24.9
12. U9 - (TF)IC.SMD.SSOP48 Chipset.INTEL.EP82562ET		100	86.1	56.1	16.1
13. U19 - (TF)IC.SMD.QFP128P Super I/O.ITE.IT8712F-A/IX-L		100	86.6	56.6	16.6
14. L8 - (TF)INDUCTOR.3.3uH.20%..VISHAY.IHLP2525CZRZ3R3M01		125	96.1	66.1	26.1
15. FWH3 - (TF)Flash PLCC BIOS.512k.CS:C723h.ETX-821.Rev 0.7.for PMC Star 2020.		100	87.7	57.7	17.7
16. U2 - (TF)IC.SMD.SSOP 56P.CLOCK GENERATOR.ICS.ICS952601FLFT		100	90.6	60.6	20.6
17. U42 - (TF)IC.SMD TFBGA.160P.PCI to ISA Bridge Chip.ITE.IT8888G-L		100	100.4	70.4	30.4
18. U21 - (TF)IC.SMD SO-8.5V Supervisory Circuits.ANALOG DEVICES.ADM706ARZ		100	86.8	56.8	16.8
19. Memory (wide temp.)		85	88.9	58.9	18.9
20. U11 -(TF)IC.SMD LQFP 48Pin.6 Channel AC'97 Audio Codec.REALTEK.ALC655-LF		100	101.5	71.5	31.5
21. Control Box Inside Air Temperature		N/A	68.2	38.2	-1.8
22. CFD Surface (wide temp.)		85	68.1	38.1	-1.9
23. Control Box Surface – 1		N/A	63.7	33.7	-6.3
24. Control Box Surface – 2		N/A	62.8	32.8	-7.2
25. Chamber Air Temperature		N/A	55.4	25.4	-14.6
<b>Any Tm value showed in red words which meaning the value over the Tc + 5 degree C of this device specification.</b>					

## Sample Configuration & Quantity Under Test:

Quantity: 1 (AEC-6905)

## Test Result:

No problem was found during the temperature cycle operation test.

**Test Date:** 09-19~21-2007

**Test Product:** AEC-6905

**Test Site:** AAEON QA Internal Lab.

**Performed By:** Rex Chang

**Test Standard:** Reference IEC 68-2-2 Testing procedures  
Test Bb: Dry Heat Test (Non-operation)

**Test Equipment:**

Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-A4C-100  
Date of Calibration: 06/20/07  
Serial Number: 3188

**Testing Item:**

1. Test Temperature: 70
2. Test Times: 48Hrs
3. Test Software: Windows XP Embedded / Run PassMark Burn In Test 5.1 Pro
4. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (AEC-6905)

**Test Result:**

No problem was found after the high temperature storage test.

# Low temperature storage test

**Test Date:** 09-21~23-2007

**Test Product:** AEC-6905.

**Test Site:** AAEON QA Internal Lab.

**Performed By:** Rex Chang

**Test Standard:** Reference IEC 68-2-1 Testing procedures  
Test Ab: Cold Test (Non-operation)

**Test Equipment:**

Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-A4C-100  
Date of Calibration: 06/20/07  
Serial Number: 3188

**Testing Item:**

1. Test Temperature: -20
2. Test Times: 48Hrs
3. Test Software: Windows XP Embedded / Run PassMark Burn In Test 5.1 Pro
4. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (AEC-6905)

**Test Result:**

No problem was found after the low temperature storage test.



**Test Date:** 09-23~25-2007

**Test Product:** AEC-6905

**Test Site:** AAEON QA Internal Lab.

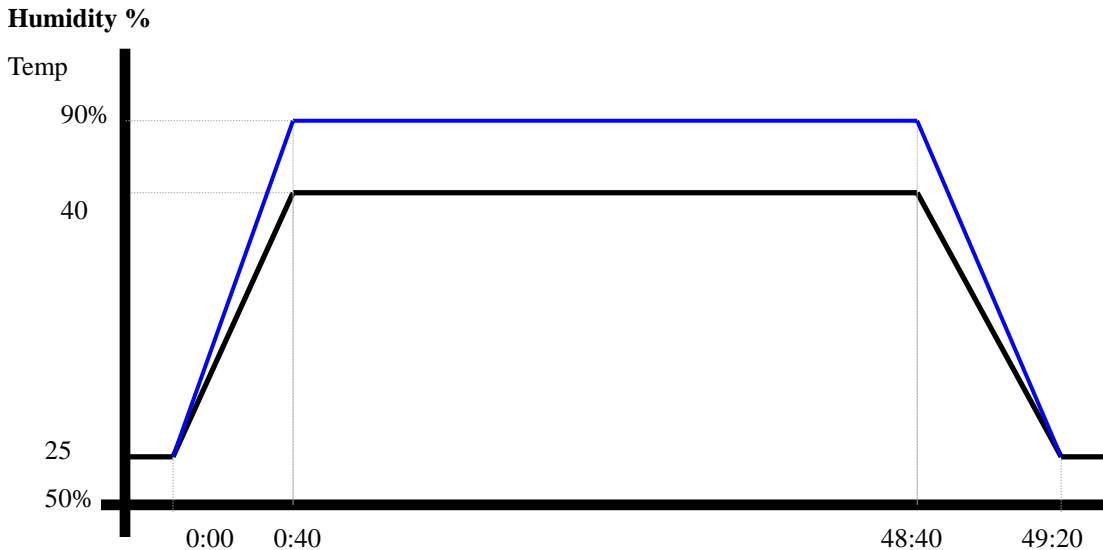
**Performed By:** Rex Chang

**Test Standard:** Reference IEC 68-2-3 Testing procedures  
Test Ca: Damp heat, steady state (Non-operation)

**Test Equipment:**  
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-A4C-100  
Date of Calibration: 06/20/07  
Serial Number: 3188

**Testing Item:**

1. Test Temperature: 40
2. Test Humidity: 90%RH
3. Test Times: 48Hrs
4. Test Software: Windows XP Embedded / Run PassMark Burn In Test 5.1 Pro
5. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**  
Quantity: 1 (AEC-6905)

**Test Result:**  
No problem was found after the humidity storage test.

# Cold start and hot start test

**Test Date:** 09-26~27-2007

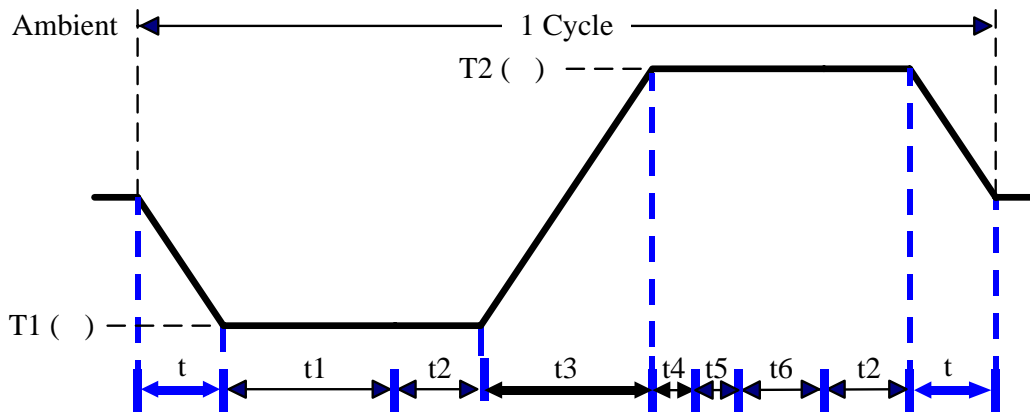
**Test Product:** AEC-6905

**Test Site:** AAEON QA Internal Lab.

**Test Standard:** Reference IEC 68-2-14 Testing procedures  
Test Nb: Change of temperature Test

**Test Equipment:**  
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-A4C-100  
Date of Calibration: 06/20/07  
Serial Number: 3188

**Test Condition:**



Parameters	Description
T1	-20
T2	60
t1	4 hrs
t2, t6	2 hrs
t4, t5	1hrs
t, t3	2 /min
n (Cycle)	1

t = temprature slope  
t , t1, t6: Power Off  
t2: Power on/off test 10 times (on 2 min / off 5min)  
t3, t4: Run PassMark Burn In Test 5.1 Pro  
t5: Win XP Embedded Software restart test 3 times  
Test Software: Windows XP Embedded

**Test Result:**

- a. No problem was found during the cold start test.
- b. No problem was found during the hot start test.